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Complete If Known

Application Number	10/812,155-Conf. #2941
Filing Date	March 29, 2004
First Named Inventor	Keisuke Inoue
Art Unit	2115
Examiner Name	T. C. Lee

Attorney Docket Number

SCEI 3.0-200

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY 06-12-2005	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
SS	AA*	US-2003/0110012-A1	10-12-2004	Orenstien et al.	
SS	AB*	US-2003/0229662-A1	12-11-2003	Luick	
SS	AC*	US-2005/0278520-A1	12-15-2005	Hirai et al.	
SS	AD*	US-2004/0003309-A1	01-01-2004	Cai et al.	
SS	AE*	US-6,269,043-B1	07-31-2001	Batcher	
SS	AF*	US-6,192,479-B1	02-20-2001	Ko	

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
SS	BA	WO-03/083693-A	10-09-2003	FUJITSU LIMITED		**
SS	BB	JP-08-016531-A	01-19-1998	HITACHI LTD		**
SS	BC	JP-10-240704-A	09-11-1998	RICOH CO LTD		**

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. *CITE NO.: Those application(s) which are marked with an single asterisk (*) next to the Cite No. are not supplied (under 37 CFR 1.88(a)(2)(ii)) because that application was filed after June 30, 2003 or is available in the IFW. ¹Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 801.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
SS	CA	SEONGMOO HEO et al, "Reducing Power Density Through Activity Migration", Proceedings of the 2003 International Symposium on Low Power Electronics and Design, Seoul, Korea, Aug. 25-27, 2003.	**

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** - English abstract attached.

Examiner Signature 638892	/Stefan Stoynov/	Date Considered	12/23/2006
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